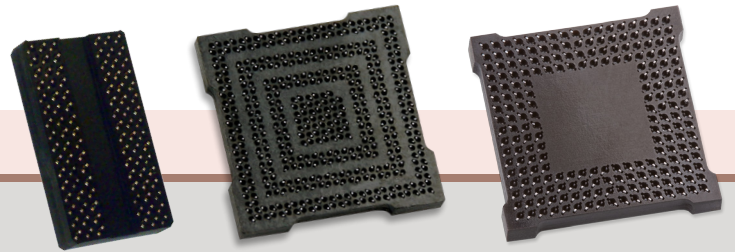


HSIO technologies

Grypper Grypper G40 Grypper G80

High performance net zero footprint
engineering test sockets

IC PACKAGE INSERTION AND REMOVAL GUIDE



Before You Begin

ABOUT THIS GUIDE

Welcome to the Grypper Test Socket IC Package Insertion and Removal Guide. This guide contains information regarding the proper IC package insertion and removal techniques for Grypper products.

NOTE



The information contained in this document is considered a general guideline only.

NOTATIONAL CONVENTIONS

This manual uses the following conventions:

NOTE



Note is used to indicate important information about the product that is not hazard related.

CAUTION



Caution is used to indicate the presence of a hazard which **will** or **can** cause minor personal injury or property damage if the warning is ignored.

WARNING



Warning is used to indicate the presence of a hazard which **can** cause severe personal injury, death or substantial property damage if the warning is ignored.

DANGER



Danger is used to indicate the presence of a hazard which **will** cause severe personal injury, death or substantial property damage if the warning is ignored.

WHERE TO GET MORE INFORMATION

More information is available from these sources:

HSIO Technologies test socket support team stands ready to assist our valued test socket customers. Our primary socket support team is based at our Maple Grove, Minnesota, USA office and is available at 1-763-447-6260 from 8:00AM - 5:00PM CST. If you require after hours support or are interested in regional support, please view our worldwide locations page.

World Wide Web: HSIO Technologies maintains an active site on the World Wide Web at www.HSIOtech.com. The site contains current information about the company and locations of sales offices, new and existing products, contacts for sales, service, and technical support information. You can also send e-mail to HSIO Technologies using the web site. Requests for sales, service, and technical support information receive prompt response.

NOTE



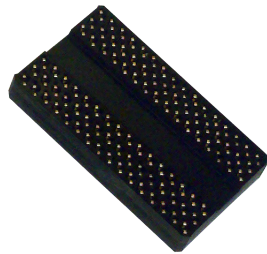
When requesting technical support through the website or e-mail, please be sure to include all nomenclature engraved on the test socket, and a detailed description of the problem. This information will allow us to serve you better.

Chapter 1

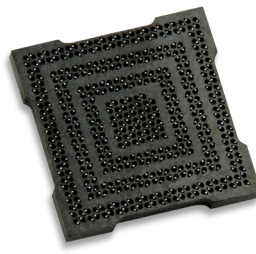
Overview

COMPONENT TERMINOLOGY

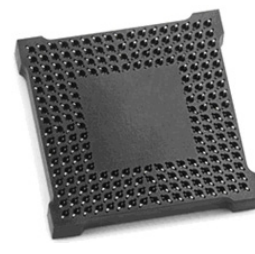
Grypper products test sockets consist of one standard part: the test socket assembly.



*Grypper test socket assembly:
without solder balls*

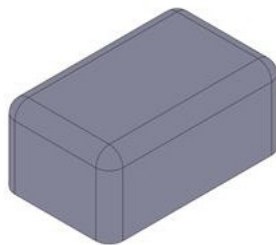


*Grypper G40 test socket
assembly: solder balls attached*



*Grypper G80 test socket
assembly: without solder balls*

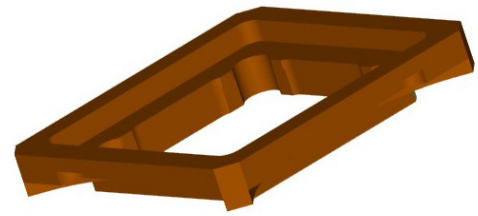
Additional components used with your test socket include the device press and the device extraction tool. An alignment frame is also provided with G40 product.



Device press



Device extraction tool



Alignment frame

SUPPLIES REQUIRED

1. Loadboard/PCB with test socket
2. Alignment frame (provided with G40 product)
3. Device press (optional)
4. Device extraction tool (optional)
5. IC package
6. Vacuum pen (optional)
7. Compressed air source (dry and clean)
8. Lint-free cloth
9. Eye protection
10. 10x magnification minimum (optional)

Chapter 2

IC Package Insertion and Removal Procedure

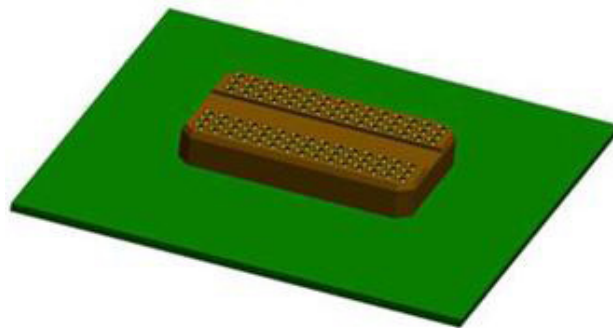
Before installing the IC package, the test socket must be mounted to the loadboard/ PCB.

WARNING



Inserting the IC package into the Grypper test socket prior to attaching the test socket to the loadboard/PCB may damage the test socket.

See the Grypper G40 Test Socket Attachment and Removal Guide (PN 700001-0001) for details.



IC PACKAGE INSERTION

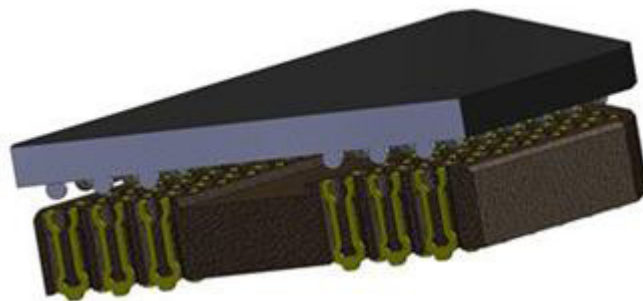
A pre-attachment bake (desiccation) ensures that the test sockets are moisture-free.

WARNING



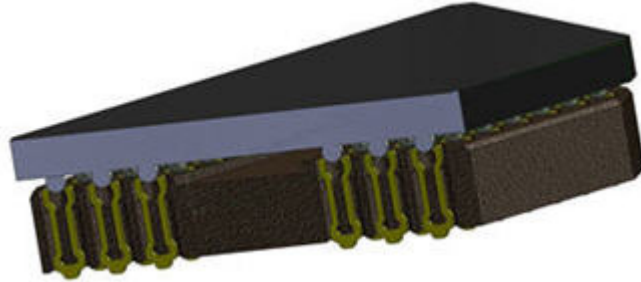
Always use eye protection when working with compressed air.

1. Use compressed air to remove any loose debris from test socket.
2. Orient the ball pattern on the IC package to align with the contacts pattern on the test socket.

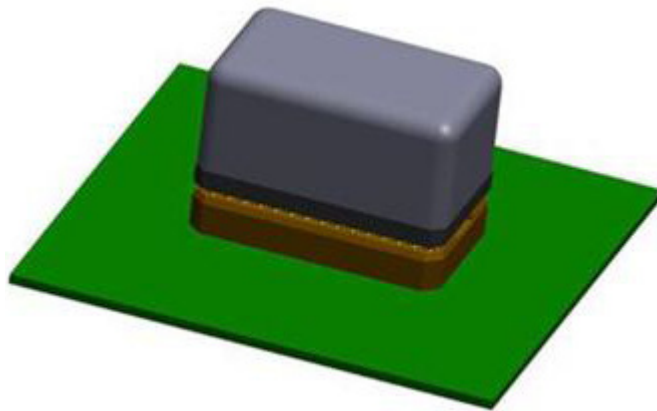


3. Gently place the IC package on the top of the test socket.

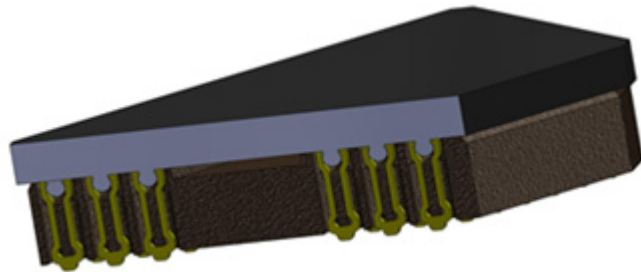
4. Use your finger to gently move the IC package in both the x and y directions to ensure that the solder balls on the IC package are aligned with the contacts on the test socket. The IC package should settle into position.



5. Use 10x minimum magnification to visually verify that the solder balls are in the proper location.
6. Provide adequate support to the bottom (opposite the test socket side) of the loadboard/PCB to prevent flexing.
7. Place the device press on the IC package (optional).



8. Use your thumb to apply downward pressure (in the z direction) on the IC package press until you hear or feel a “snap”.



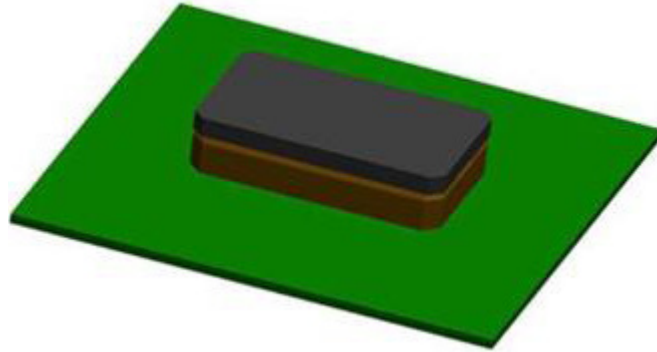
NOTE



If you cannot attain adequate force to fully seat the package, an arbor press can be used. Exercise caution, however, to prevent damage to test system components.

9. Remove the device press from the IC package.

10. Use 10x minimum magnification to visually verify that the IC package is fully seated in the test socket.
11. The loadboard/PCB, test socket and IC package are now ready for testing.



IC PACKAGE REMOVAL

1. Locate the device extraction tool provided with the test socket.
2. Orient the tip of the device extraction tool toward the loadboard/PCB.
3. Insert the tip of the tool into one of the test socket sides so it interfaces with the lower edge of the IC package.

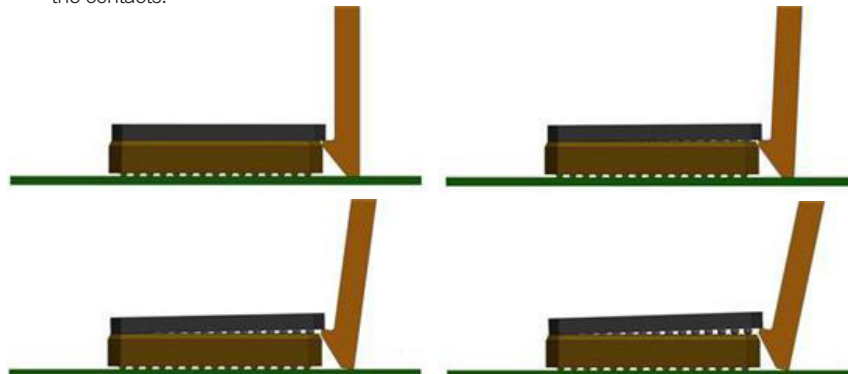
NOTE



Each end of the device extraction tool is geometrically different. The shorter end of the extraction tool is typically used for IC packages exhibiting a solder ball pitch of 0.40 and 0.50mm, while the longer end is used for IC packages exhibiting a solder ball pitch >0.50 mm.



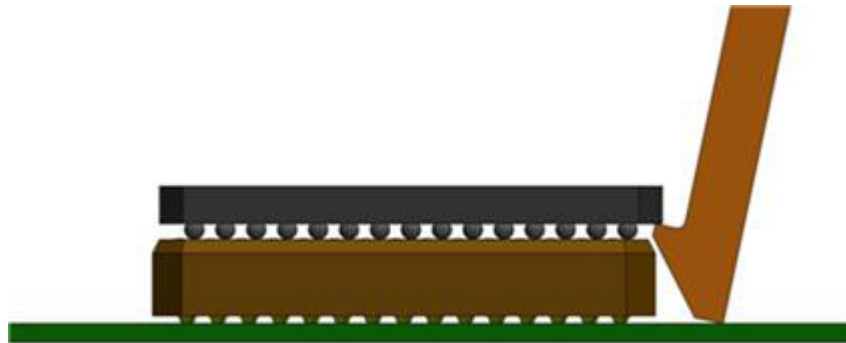
4. Gently rotate the top of the extraction tool away from the test socket to lift the IC package away from the contacts.



NOTE

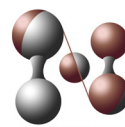


To prevent potential damage to the IC package, place your hand slightly above the IC package to capture it, if necessary, when it releases from the contacts.



For larger IC packages it may be necessary to repeat these steps on the opposite side of the test socket to fully release the IC package.

5. Use a vacuum pen to remove the IC package from the test socket.



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